

Application/Contro	l No.

Applicant(s)/Patent under Reexamination

10/612,760

CHEN ET AL.

Examiner

David E. Martinez

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SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
710	62	3/23/2007	DM	
370	335, 342	3/23/2007	DM	
375	145,149	3/23/2007	DM	
US PGPUB	US Patents, S, USOCR, , Derwent,	3/23/2007	DM	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East see attached	3/23/2007	DM
inventor search eDan, East, Palm	3/26/2007	DM .
710/62.ccls. 714/786,790,795.ccls. 370/465,355,252,335,342.ccls. 375/145,149,363-366.ccls. with keywords and text search	3/23/2007	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	3/23/2007	DM
google, google patents	3/23/2007	DM
PLUS Search	3/23/2007	DM